## Application/Control No. Applicant(s)/Patent Under Reexamination 10/081,387 OLOVSSON, LARS **Notice of References Cited** Art Unit Examiner Page 1 of 3 Carlos Ortiz-Rodriguez 2125 **U.S. PATENT DOCUMENTS** Date Document Number \* Classification Name Country Code-Number-Kind Code MM-YYYY \* 05-2003 Dohrmann et al. 703/7 Α US-6,560,570 \* 01-2004 703/2 US-6,678,642 Budge, Kent G. В \* 08-2004 Lu et al. 703/7 С US-6,785,640 D US-US-Ε US-F US-G Н US-US-1 US-J US-Κ US-L US-М FOREIGN PATENT DOCUMENTS Document Number Date Classification Country Name Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R S Т

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